

December 1997

Fast CMOS 3.3V 16-Bit Buffer/Line Driver

Features

- Advanced 0.6 micron CMOS Technology
- 5V Tolerant Inputs and Outputs
- Supports Live Insertion of PCBs
- 2.0V to 3.6V V_{CC} Supply Range
- Balanced 24mA Output Drive
- Low Ground Bounce Outputs
- ESD Protection Exceeds 2000V, HBM; 200V, MM
- Functionally Compatible with FCT3, LVC, LVT, and 74 Series Logic Families

Description

The CD74LCX16244 is a 16-bit buffer/line driver designed for driving high capacitive memory loads. With its balanced-drive characteristics, this high-speed, low power device provides lower ground bounce, transmission line matching of signals, fewer line reflections and lower EMI and RFI effects. This makes it ideal for driving on-board buses and transmission lines. This device is designed with three-state controls to operate in a Quad-Nibble, Dual-Byte, or a single 16-bit word mode.

The CD74LCX16244 can be driven from either 3.3V or 5.0V devices allowing this device to be used as a translator in a mixed 3.3/5.0V system.

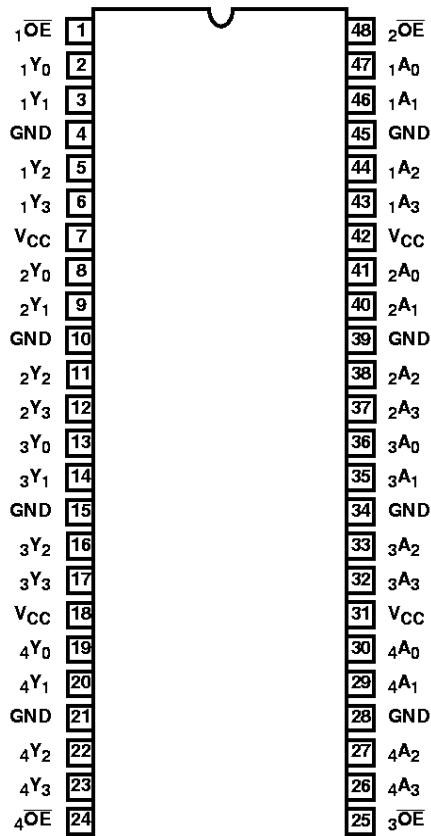
Ordering Information

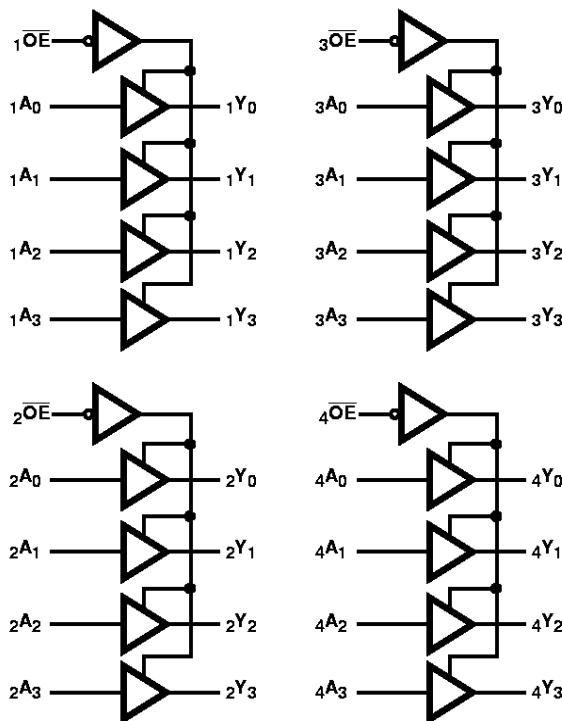
PART NUMBER	TEMP. RANGE (°C)	PACKAGE	PKG. NO.
CD74LCX16244MT	-40 to 85	48 Ld TSSOP	M48.240-P
CD74LCX16244SM	-40 to 85	48 Ld SSOP	M48.300-P

NOTE: When ordering, use the entire part number. Add the suffix 96 to obtain the variant in the tape and reel.

Pinout

CD74LCX16244
(SSOP, TSSOP)
TOP VIEW



Functional Block Diagram

TRUTH TABLE (NOTE 1)

INPUTS		OUTPUTS
$x\bar{OE}$	x^A_x	x^Y_x
L	L	L
L	H	H
H	X	Z

NOTE:

1. H = High Voltage Level
- L = Low Voltage Level
- X = Don't Care
- Z = High Impedance

Pin Descriptions

PIN NAME	DESCRIPTION
$x\bar{OE}$	Three-State Output Enable Inputs (Active LOW)
x^A_x	Inputs
x^Y_x	Three-State Outputs
GND	Ground
V_{CC}	Power

Absolute Maximum Ratings

DC Input Voltage	-0.5V to 7.0V
DC Output Current	120mA

Operating Conditions

Temperature Range	-40°C to 85°C
Supply Voltage to Ground Potential Inputs and V_{CC} Only.....	-0.5V to 7.0V
Supply Voltage, V_{CC} Operating	2.0V (Min), 3.6V (Max)
Data Retention	1.5V (Min), 3.6V (Max)
Supply Voltage to Ground Potential Outputs and D/O Only.....	-0.5V to 7.0V

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

2. θ_{JA} is measured with the component mounted on an evaluation PC board in free air.

Electrical Specifications

PARAMETER	SYMBOL	(NOTE 3) TEST CONDITIONS		MIN	(NOTE 4) TYP	MAX	UNITS
DC ELECTRICAL SPECIFICATIONS Over the Operating Range, $T_A = -40^\circ\text{C}$ to 85°C , $V_{CC} = 2.7\text{V}$ to 3.6V							
Input HIGH Voltage	V_{IH}	Guaranteed Logic HIGH Level		2.0	-	-	V
Input LOW Voltage (Input and I/O Pins)	V_{IL}	Guaranteed Logic LOW Level		-	-	0.8	V
Output HIGH Voltage	V_{OH}	$V_{CC} = 2.7\text{V}$ to 3.6V	$I_{OH} = -0.1\text{mA}$	$V_{CC} - 0.2$	-	-	V
		$V_{CC} = 2.7\text{V}$	$I_{OH} = -12\text{mA}$	2.2	-	-	V
		$V_{CC} = 3.0\text{V}$	$I_{OH} = -18\text{mA}$	2.4	-	-	V
			$I_{OH} = -24\text{mA}$	2.2	-	-	V
Output LOW Voltage	V_{OL}	$V_{CC} = 2.7\text{V}$ to 3.6V	$I_{OL} = 0.1\text{mA}$	-	-	0.2	V
		$V_{CC} = 2.7\text{V}$	$I_{OL} = 12\text{mA}$	-	-	0.4	V
		$V_{CC} = 3\text{V}$	$I_{OL} = 16\text{mA}$	-	-	0.4	V
			$I_{OL} = 24\text{mA}$	-	-	0.55	V
Clamp Diode Voltage	V_{IK}	$V_{CC} = \text{Min}$, $I_{IN} = -18\text{mA}$		-	-0.7	-1.2	V
Input Current	I_I	$V_{CC} = 2.7\text{V}$ to 3.6V	$0 \leq V_I \leq 5.5\text{V}$	-	-	± 5	μA
High Impedance Output Current (Three-State)	I_{OZ}	$V_{CC} = 2.7\text{V}$ to 3.6V	$0 \leq V_O \leq 5.5\text{V}$ $V_I = V_{IH}$ or V_{IL}	-	-	± 5	μA
Power Down Disable	I_{OFF}	$V_{CC} = 0\text{V}$	V_{IN} or $V_{OUT} \leq 5.5\text{V}$	-	-	10	μA
Quiescent Power Supply Current	I_{CC}	$V_{CC} = \text{Max}$	$V_{IN} = \text{GND}$ or V_{CC}	-	0.1	10	μA
Quiescent Power Supply Current TTL Inputs HIGH	ΔI_{CC}	$V_{CC} = \text{Max}$	$V_{IN} = V_{CC} - 0.6\text{V}$ (Note 5)	-	-	500	μA
CAPACITANCE							
Input Capacitance (Note 6)	C_{IN}	$V_{CC} = \text{Open}$, $V_{IN} = 0\text{V}$ or V_{CC}		-	7	-	pF
Output Capacitance (Note 6)	C_{OUT}	$V_{CC} = 3.3\text{V}$, $V_{IN} = 0\text{V}$ or V_{CC}		-	8	-	pF
Power Dissipation Capacitance (Note 7)	C_{PD}	$V_{CC} = 3.3\text{V}$, $V_{IN} = 0\text{V}$ or V_{CC} , $f = 10\text{MHz}$		-	20	-	pF

Switching Specifications Over Operating Range

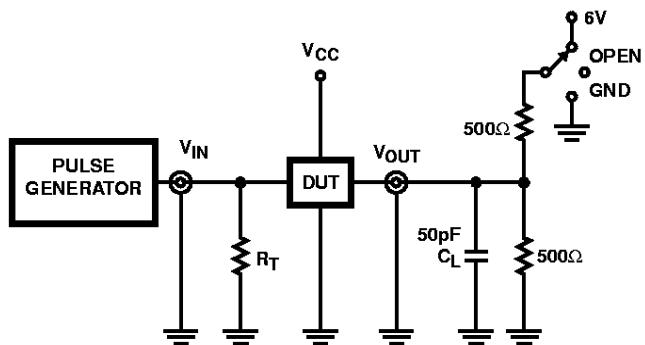
PARAMETER	SYMBOL	TEST CONDITIONS	$V_{CC} = 3.3V \pm 0.3V$		$V_{CC} = 2.7V$		UNITS
			MIN	MAX	MIN	MAX	
Propagation Delay D_{XX} to O_{XX}	t_{PLH}, t_{PHL}	$C_L = 50\text{pF}$ $R_L = 500\Omega$	1.5	4.8	1.5	5.2	ns
Output Enable Time	t_{PZH}, t_{PZL}		1.5	5.5	1.5	6.3	ns
Output Disable Time (Note 10)	t_{PHZ}, t_{PLZ}		1.5	5.4	1.5	5.7	ns
Output Skew (Note 11)	$t_{SK(O)}$		-	1.0	-	-	ns

Dynamic Switching Characteristics $T_A = 25^\circ\text{C}$

PARAMETER	SYMBOL	(NOTE 12) TEST CONDITIONS	TYP	UNITS
Dynamic LOW Peak Voltage	V_{OLP}	$V_{CC} = 3.3V, C_L = 50\text{pF}, V_{IH} = 3.3V, V_{IL} = 0V$	0.8	V
Dynamic LOW Valley Voltage	V_{OLV}	$V_{CC} = 3.3V, C_L = 50\text{pF}, V_{IH} = 3.3V, V_{IL} = 0V$	0.8	V

NOTES:

3. For conditions shown as Max or Min, use appropriate value specified under Electrical Specifications for the applicable device type.
4. Typical values are at $V_{CC} = 3.3V, 25^\circ\text{C}$ ambient and maximum loading.
5. Per TTL driven input; all other inputs at V_{CC} or GND.
6. This parameter is determined by device characterization but is not production tested.
7. C_{PD} determines the no-load dynamic power consumption per latch. It is obtained by the following relationship:
 P_D (total power per latch) = $V_{CC}^2 f_i (C_{PD} + C_L)$ where f_i = input frequency, C_L = output load capacitance, V_{CC} = supply range.
8. See test circuit and waveforms.
9. Minimum limits are guaranteed but not tested on Propagation Delays.
10. This parameter is guaranteed but not production tested.
11. Skew between any two outputs, of the same package, switching in the same direction. This parameter is guaranteed by design.
12. Measured with n-1 outputs switching from High-to-Low or Low-to-High. The remaining output is measured in the LOW state.

Test Circuits and Waveforms**SWITCH POSITION**

TEST	SWITCH
t _{PZL} , t _{PZL} , Open Drain	6V
t _{PHZ} , t _{PZH}	GND
t _{PLH} , t _{PHL}	Open

DEFINITIONS:C_L = Load capacitance, includes jig and probe capacitance.R_T = Termination resistance, should be equal to Z_{OUT} of the Pulse Generator.**NOTE:**

13. Pulse Generator for All Pulses: Rate \leq 1.0MHz; Z_{OUT} \leq 50Ω;
 $t_f, t_r \leq 2.5\text{ns}$.

FIGURE 1. TEST CIRCUIT

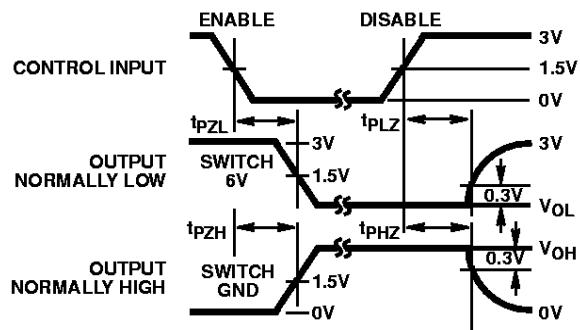


FIGURE 2. ENABLE AND DISABLE TIMING

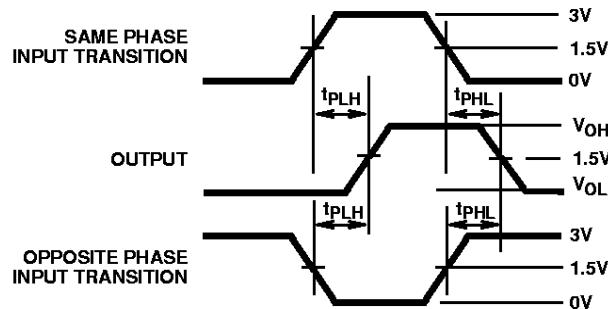


FIGURE 3. PROPAGATION DELAY